

March 2016

FDP51N25 / FDPF51N25 N-Channel UniFETTM MOSFET 250 V, 51 A, 60 m Ω

Features

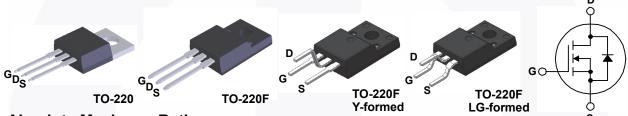
- $R_{DS(on)}$ = 48 $m\Omega(Typ.)$ @ V_{GS} = 10 V, I_D = 25.5 A
- Low Gate Charge (Typ. 55 nC)
- Low C_{rss} (Typ. 63 pF)

Applications

- PDP TV
- Lighting
- · Uninterruptible Power Supply
- · AC-DC Power Supply

Description

UniFETTM MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Para	meter	FDP51N25	FDPF51N25 FDPF51N25YDTU FDPF51N25RDTU	Unit
V_{DSS}	Drain-Source Voltage			V	
I _D	Drain Current	- Continuous (T _C = 25°C) - Continuous (T _C = 100°C)	51 30	51* 30*	A A
I_{DM}	Drain Current	- Pulsed (Note 1)	204	204*	Α
V _{GSS}	Gate-Source voltage		:	V	
E _{AS}	Single Pulsed Avalanche Energy (Note 2)			mJ	
I _{AR}	Avalanche Current (Note 1)			Α	
E _{AR}	Repetitive Avalanche Energy (Note 1)			mJ	
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t=0.3sec; $T_C = 25^{\circ}C$)		N/A	2500	٧
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5		V/ns
P_D	Power Dissipation	(T _C = 25°C) - Derate Above 25°C	320 3.7	38 0.3	W W/°C
T _{J,} T _{STG}	Operating and Storage Temperature Range		-55	°C	
T _L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			°C	

^{*}Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	FDP51N25	FDPF51N25 FDPF51N25YDTU FDPF51N25RDTU	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.39	3.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	62.5	°C/W

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Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FDP51N25	FDP51N25	TO-220	Tube	N/A	N/A	50 units
FDPF51N25	FDPF51N25	TO-220F	Tube	N/A	N/A	50 units
FDPF51N25YDTU	FDPF51N25	TO-220F (Y-formed)	Tube	N/A	N/A	50 units
FDPF51N25RDTU	FDPF51N25	TO-220F (LG-formed)	Tube	N/A	N/A	50 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

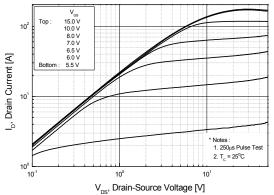
Symbol	Parameter	Conditions		Тур.	Max.	Unit
Off Charac	teristics			II.	1	
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA, T _J = 25 °C				V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.25		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 250 V, V _{GS} = 0 V V _{DS} = 200 V, T _C = 125°C			1 10	μ Α μ Α
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0V			-100	nA
On Charac	teristics		(
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 25.5 A		0.048	0.060	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 25.5 A		43		S
Dynamic C	Characteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz		2620	3410	pF
C _{oss}	Output Capacitance			530	690	pF
C _{rss}	Reverse Transfer Capacitance			63	90	pF
Switching	Characteristics					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 125 \text{ V}, I_D = 51 \text{ A},$ $V_{GS} = 10 \text{ V}, R_G = 25 \Omega$ (Note 4)		62	135	ns
t _r	Turn-On Rise Time			465	940	ns
$t_{d(off)}$	Turn-Off Delay Time			98	205	ns
t _f	Turn-Off Fall Time			130	270	ns
Qg	Total Gate Charge	V _{DS} = 200 V, I _D = 51 A,		55	70	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		16		nC
Q _{gd}	Gate-Drain Charge	(Note 4)		27		nC
Drain-Soul	rce Diode Characteristics and Maximur	n Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				51	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				204	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 51 A			1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 51 \text{ A,}$ $dI_F/dt = 100 \text{ A/}\mu\text{s}$		178		ns
Q _{rr}	Reverse Recovery Charge			4.0		μС

Notes:

- 1. Repetitive rating: pulse-width limited by maximum junction temperature.
- 2. L = 0.68 mH, I_{AS} = 51 A, V_{DD} = 50 V, R_G = 25 Ω starting T_J = 25°C.
- 3. $I_{SD} \le 51$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, starting $T_J = 25^{\circ}$ C.
- 4. Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics



Drain Current and Gate Voltage

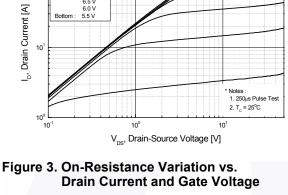
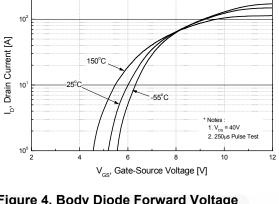


Figure 2. Transfer Characteristics



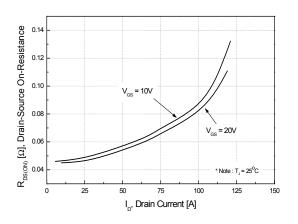


Figure 5. Capacitance Characteristics

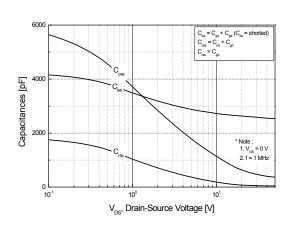


Figure 6. Gate Charge Characteristics

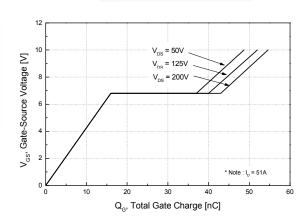


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue



1. V_{cs} = 0V

2. 250μs Pulse Test

Reverse Drain Current [A]

_, R

Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

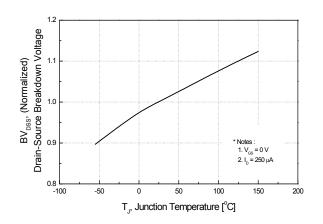


Figure 9-1. Maximum Safe Operating Area for FDP51N25

Figure 8. On-Resistance Variation vs. Temperature

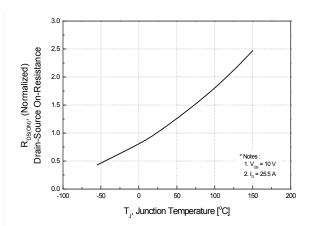


Figure 9-2. Maximum Safe Operating Area for FDPF51N25 / FDPF51N25YDTU

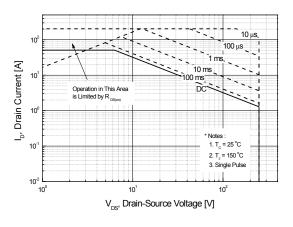
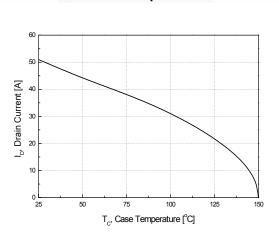
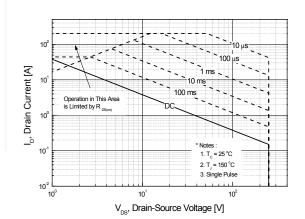


Figure 10. Maximum Drain Current vs. Case Temperature





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Typical Performance Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve for FDP51N25

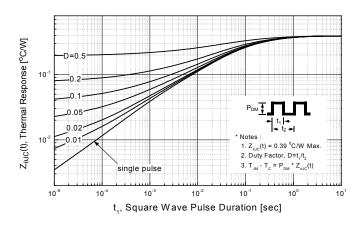
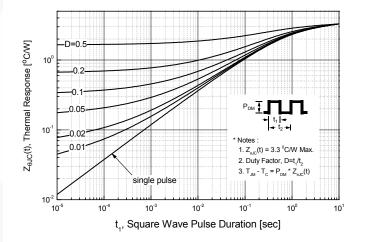


Figure 11-2. Transient Thermal Response Curve for FDPF51N25 / FDPF51N25YDTU



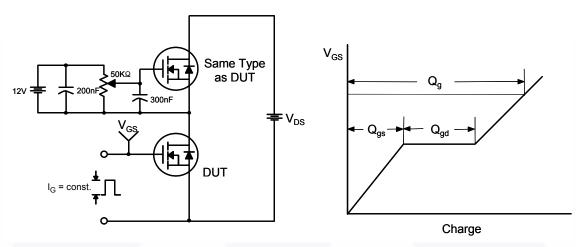


Figure 12. Gate Charge Test Circuit & Waveform

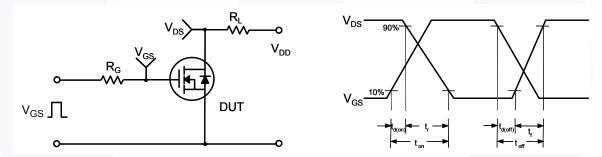


Figure 13. Resistive Switching Test Circuit & Waveforms

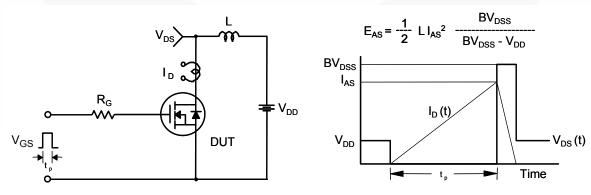


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

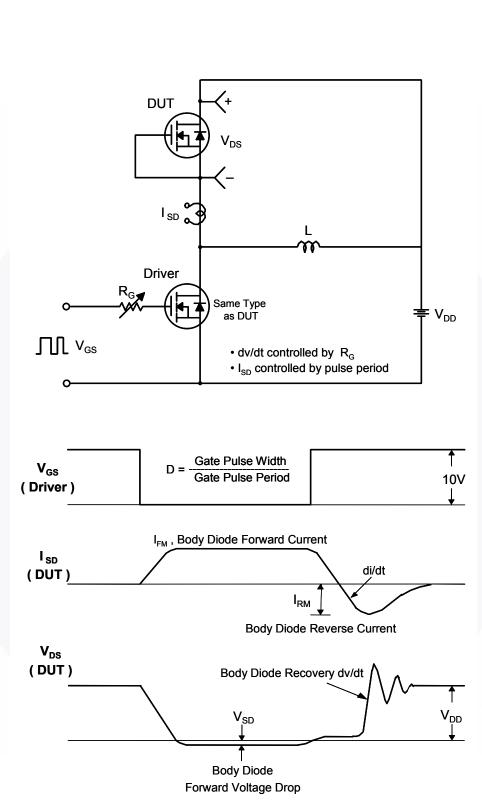
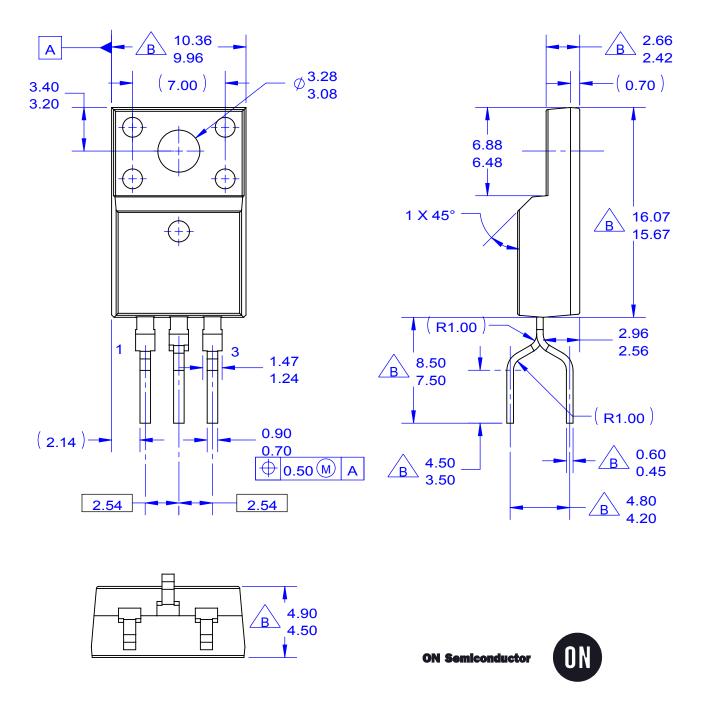


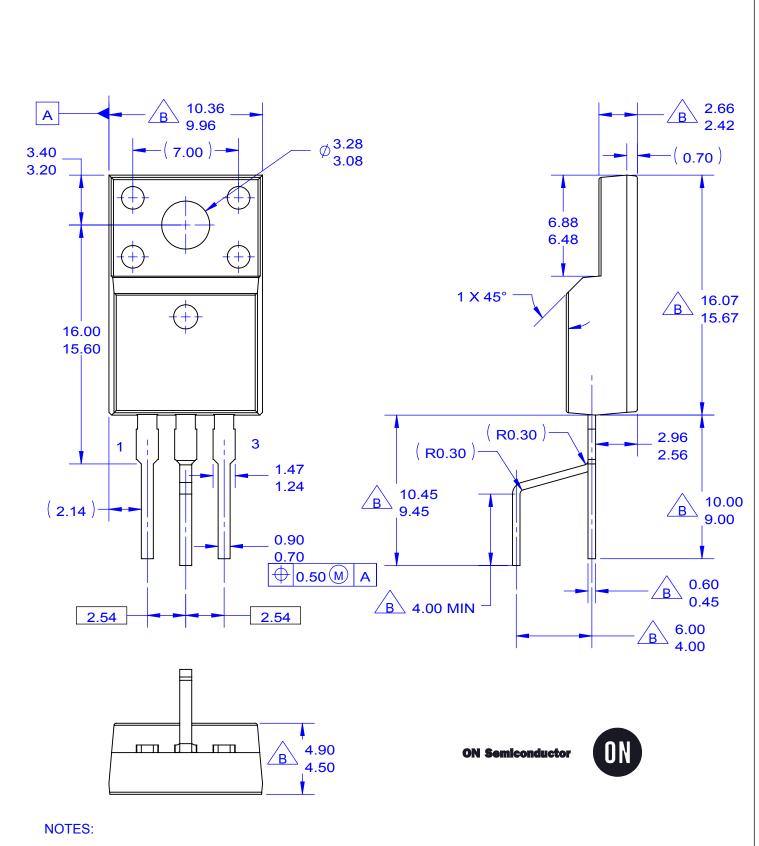
Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



NOTES:

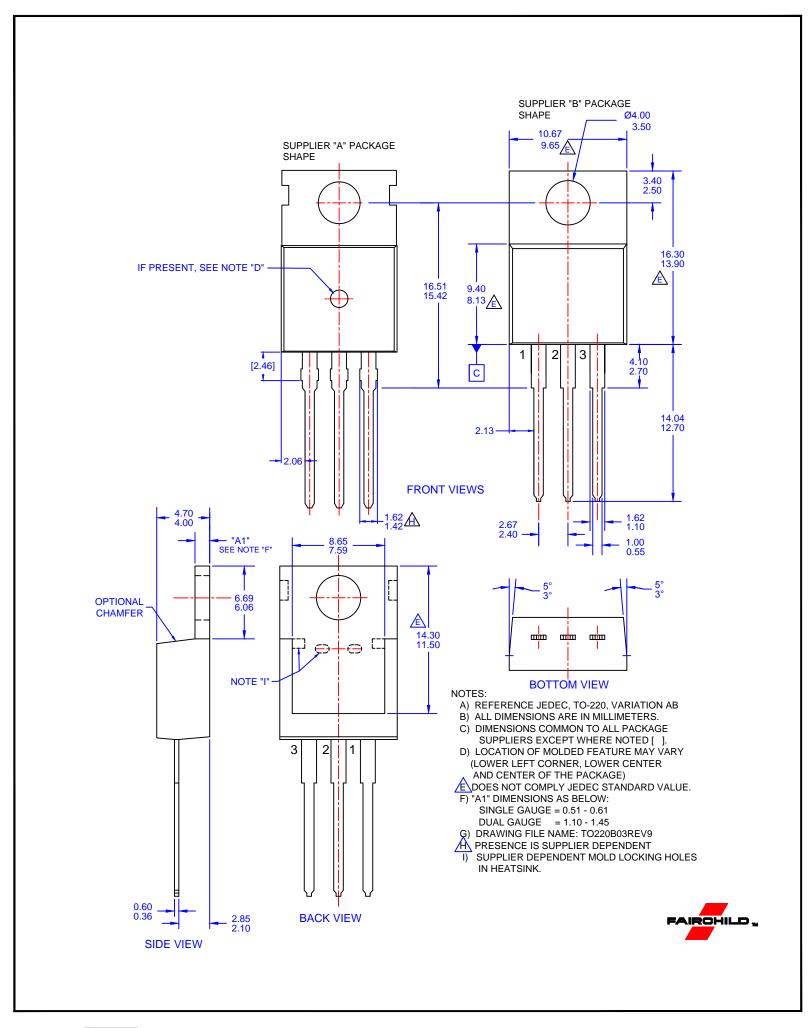
- A. EXCEPT WHERE NOTED CONFORMS TO
- EIAJ SC91A.

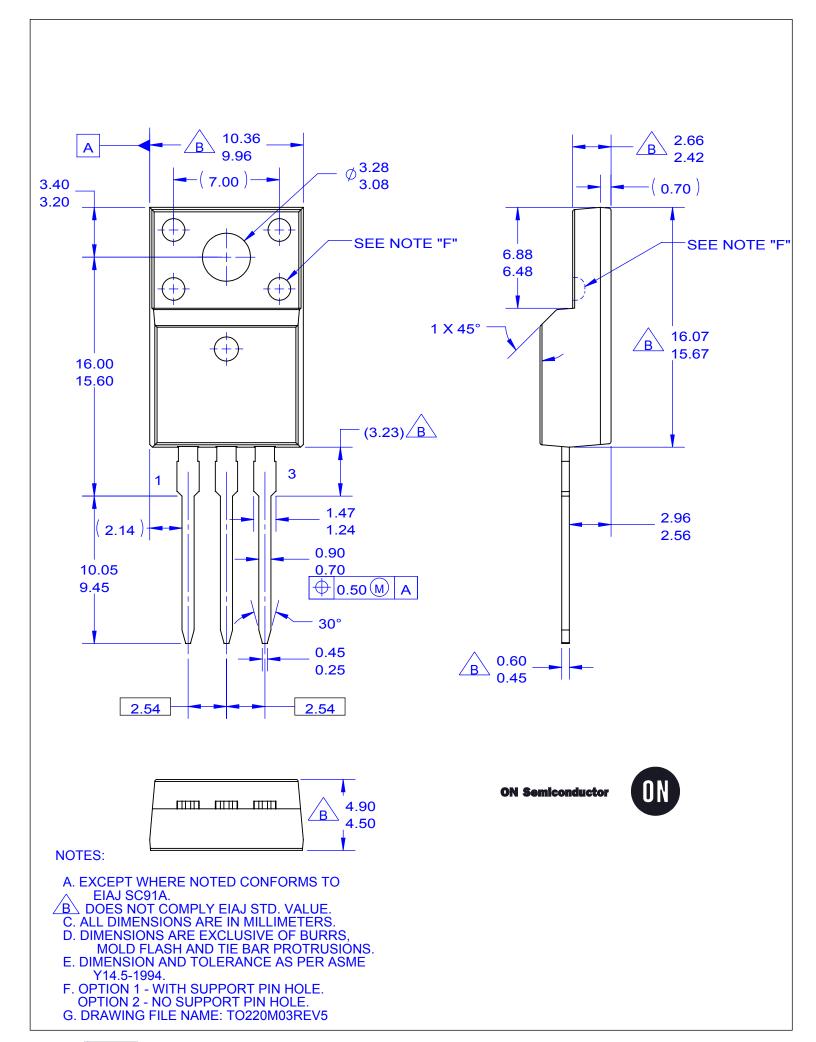
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 C. ALL DIMENSIONS ARE IN MILLIMETERS.
- D. DIMENSIONS ARE EXCLUSIVE OF BURRS
- MOLD FLASH AND TIE BAR PROTRUSIONS. E. DIMENSION AND TOLERANCE AS PER ASME Y14.5-1994.
- F. DRAWING FILE NAME: TO220N03REV2



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- D. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS.
- E. DIMENSION AND TOLERANCE AS PER ASME Y14.5-1994.
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